



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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7/30/03
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Applicant: Jorg-Thomas Zettler
Serial No.: 09/998,446
Filed: Nov. 30, 2001
For: METHOD FOR MEASURING
CHARACTERISTICS, ESPECIALLY
THE TEMPERATURE OF A
MULTI-LAYER MATERIAL WHILE
THE LAYERS ARE BEING BUILT UP
Art Unit: 2877

Examiner: Lyons, Michael A.

CERTIFICATE OF MAILING BY "EXPRESS MAIL"

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Date of Deposit: July 16, 2003

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Print Name: ERIKA McDOUGALD

Signature: Erika McDougald

Commissioner for Patents
Alexandria, VA 22313-1450

SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT

Sir:

The attention of the Examiner is directed to the enclosed document submitted under 1.97(c)(2) as identified below.

1. K.P. KILLEEN and W.G. BREILAND, "In Situ Spectral Reflectance Monitoring of III-V Epitaxy," Journal of Electronic Materials, Vol. 23, No. 2, 1994, pages 179-183.

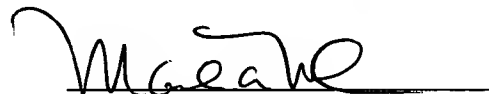
The foregoing document is listed on the annexed form PTO Form SB/08B and a copy is enclosed herewith.

The Examiner is invited to consider this material in the examination of the present application and to conduct an independent search.

A fee as set forth in § 1.17(p) is enclosed. The Commissioner is hereby authorized to charge any fees additional fee which may be due, and to credit any overpayment, to Deposit Account No. 14-1263. A duplicate copy of this paper is enclosed.

Please stamp and return the enclosed postcard to acknowledge receipt of the foregoing.

Respectfully submitted,


Mark A. Montana
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July 16, 2003

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